## INTERNATIONAL STANDARD



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## **Identification cards — Card service life —** Part 1:

## Application profiles and requirements

Cartes d'identification — Durée de vie des cartes —

Partie 1: Profils d'application et exigences

## iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>ISO/IEC 24789-1:2012</u> https://standards.iteh.ai/catalog/standards/sist/9f2fb7a0-59fe-4437-afl e-8fd153e32241/iso-iec-24789-1-2012



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## Contents

Forew	word	iv
Introd	duction	v
1	Scope	1
2	Normative references	1
3 3.1 3.2	Terms, definitions and abbreviated terms Terms and definitions Abbreviated terms	1 1 2
4 4.1 4.2	Card applications and their profiles Determination of the application profile Determination of the aging and usage classes	2 2 7
5 5.1 5.2 5.3	Determination of the evaluation regime General Evaluation regime using stand alone methods Evaluation regime using evaluation sequences	7 7 8 9
Anne	ex A (informative) Example application profiles	15
Anne	ex B (informative) Example evaluation regimes	44

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## Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work. In the field of information technology, ISO and IEC have established a joint technical committee, ISO/IEC JTC 1.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO and IEC shall not be held responsible for identifying any or all such patent rights.

ISO/IEC 24789-1 was prepared by Joint Technical Committee ISO/IEC JTC 1, Information technology, Subcommittee SC 17, Cards and personal identification. A RD PREVIEW

ISO/IEC 24789 consists of the following parts, under the general title *Identification cards* — Card service life:

- Part 1: Application profiles and requirements
- Part 2: Methods of evaluation 8fd153e32241/iso-iec-24789-1-2012

## Introduction

This part of ISO/IEC 24789 comprises a methodology for determining application profiles, their requirements and corresponding examples.

These application profiles and requirements are intended to guide the reader of this part of ISO/IEC 24789 on the comparative rigour of various ID card service life applications. These profiles and requirements provide a means for ranking and comparing the main factors affecting ID card service life in a manner that is suitable for evaluation using the methods defined or referenced in ISO/IEC 24789-2.

In order to accommodate existing cards, the simplest class uses, at least, characteristics and criteria defined in ISO/IEC 7810 and test method equipment and procedures defined in ISO/IEC 10373-1. Two types of cards are taken into account, cards that contain an integrated circuit and cards that do not contain an integrated circuit.

Although the equipment and parts of the procedures of certain ISO/IEC 10373-1 test methods are referenced for employment in the simulation of aging or usage in ISO/IEC 24789, such references are clearly distinguished from the normal use of ISO/IEC 10373-1. In normal use, these ISO/IEC 10373-1 test methods are applied to determine conformity to ISO/IEC 7810 and do not explicitly address application-specific requirements for card service life.

Due to a lack of field/laboratory correlation data, only limited acceptance criteria (normative application profiles and requirements) can be provided in the 2010 edition of this part of ISO/IEC 24789. However, it is anticipated that a more comprehensive set of values for acceptance levels will be available in future editions.

At the time of publishing this first edition, there is limited data to show direct equivalence to any measure of actual field use conditions. It will not be possible to establish any such equivalence until and unless a degree of quantitative correlation has been established for the ID card construction in question.

For the convenience of certain users, non-SI equivalents are given for some quantity values where these are in common use in the ID card industry. These equivalents appear in parenthesis and are for information only.

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## Identification cards — Card service life —

# Part 1: Application profiles and requirements

## 1 Scope

This part of ISO/IEC 24789 comprises a methodology for determining application profiles, their requirements and corresponding examples. It contains no additional or changed requirements for the ID card properties defined in other applicable standards. It seeks to define the relative rigour of each application defined herein in terms of a set of simple but justifiable methods of evaluation.

The purpose of ISO/IEC 24789 is to provide guidance on methods and their use to simulate a card's service life. In order to achieve this purpose, two parameters of card service life are defined: age and usage. This can be represented as a two-dimensional matrix in which each age/usage combination corresponds to a card service life class. The two parts of ISO/IEC 24789 together describe the evaluation methods to be used and their criteria.

ISO/IEC 24789 was originally developed for 1D-1 cards conforming to ISO/IEC 7810, but might be found useful in whole or in part for other types and form factors.

ISO/IEC 24789-1:2012 References are given to the corresponding methods of evaluation in SO/IEC 24789-2 and elsewhere. 8fd153e32241/iso-jec-24789-1-2012

## 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/IEC 7810, Identification cards — Physical characteristics

ISO/IEC 10373-1, Identification cards — Test methods — Part 1: General characteristics

ISO/IEC 10373-2, Identification cards — Test methods — Part 2: Cards with magnetic stripes

ISO/IEC 24789-2, Identification cards — Card service life — Part 2: Methods of evaluation

## 3 Terms, definitions and abbreviated terms

### 3.1 Terms and definitions

For the purposes of this document, the terms, definitions and abbreviated terms given in ISO/IEC 7810, ISO/IEC 10373-1, ISO/IEC 10373-2, ISO/IEC 24789-2 and the following apply.

## 3.1.1

### card service life

## CSL

period of time and usage for which a card retains the set of characteristics specified for its application under the conditions of use specified for that application from the time it is issued to the card holder

## 3.1.2

### application profile

set of parameters that, in total, define the conditions of use specified for an application

### 3.1.3

### evaluation regime

set of evaluation methods, together with their manner of combination and application

## 3.2 Abbreviated terms

- ATM Automated Teller Machine
- IC Integrated Circuit
- PICC Proximity Integrated Circuit Card
- VICC Vicinity Integrated Circuit Card

## 4 Card applications and their profiles **NDARD PREVIEW**

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## 4.1 Determination of the application profile

ISO/IEC 24789-1:2012

**4.1.1 Raw application profile**s://standards.iteh.ai/catalog/standards/sist/9f2fb7a0-59fe-4437-afle-8fd153e32241/iso-iec-24789-1-2012

Three variables are used to establish the raw application profile. These are:

- environment;
- storage;
- reader profile.

Raw application profiles have two parameters:

- age (A);
- usage (U).

NOTE Age is the time dependent parameter and usage is the stress dependent parameter (see 4.2).

To determine the application profile, define the environmental, storage and reader factors in Table 1, Table 2 and Table 3 respectively by defining the probability for each condition in the column "Probability p". The sum of probabilities for each factor shall be 1.

Next, for each condition with a probability greater than 0, calculate the age points in column "Age points" by multiplying the value in the column "Age" with the probability p in the column "Probability p". Then calculate the usage points in columns "Usage points" by multiplying the value in the column "Usage" with the probability p in the column "Probability p".

Then, calculate the sum A of all age points and the sum U of all usage points. This pair of values (A, U) is the raw application profile for the application.

Factor	Condition	Age	Usage	Probability <i>p</i> of condition (sum=1)	Age points (p x age)	Usage points (p x usage)	Examples and guidance
Temperature	Normal (5°C to 30°C)	0	0				
	Low (below 5°C)	1	0				
	High (30°C to 50°C)	2	0				
	Very high (above 50°C)	5	0				
Temperature changes	<=1 per week	0	0				
(transition between any two of the above temperature ranges)	> 1 per week and <=1 per day	2	0,6				
	> 1 per day and <=3 per day	3	0,9				
	>3 per day	5	1,5				
Relative humidity	Normal (30% - 70%)			RD PRF	VIEW		
	Dry (< 30%)		9	s itab ai			
	Humid (> 70%)	3 ai	galu	s.iten.a	)		
Daylight	None https://standards	0 <u>18</u> .iteh.ai/ca 8fd153e.	O <u>GIEC 24</u> alog/stand 2241/iso-:	<u>/89-1:2012</u> irds/sist/9f2fb7a0 ec-24789-1-201	-59fe-4437-afl( 2	<b>}</b>	Normally carried in a wallet or a bag.
	Indoor	1	0				Worn visibly as an ID badge indoors.
	Outdoor	5	0				Worn visibly as an ID badge outdoors, e.g. at a building site or as a ski-pass.
Chemicals and particulate exposure (e.g. sand and dust,	Low	0	0				Residential, office or retail environment.
oils and fats, corrosive gases, salt)	Medium	2	0				Light factory environment; outdoor ID badge usage.
	High	5	0				Car repair or heavy factory environment.
Sum ( <i>A</i> , <i>U</i> )							

## Table 1 — Environmental factors

Factor	Condition	Age	Usage	Probability <i>p</i> of condition (sum=1)	Age points (p x age)	Usage points (p x usage)	Examples and guidance
Physical stress (bending)	None	0	0				Hard plastic holder.
	Low	0	1				Wallet in purse or handbag; inserted in reader in vehicle.
	Medium	0	2				Multiple cards stacked in soft plastic holder or wallet in trouser pocket.
	High	0	5				Multiple cards shingled in wallet in trouser pocket; single card loose or in paper sleeve or in soft plastic holder in pocket or bag.
Physical stress (friction)	None	° eh S	0 TAN	DARD	PREVI	EW	Card always remains in holder, e.g. PICC.
	Low	1	( <b>stan</b> ) <u>ISC</u> .iteh.ai/cata	Jards.it	e <b>h.ai)</b> <u>)12</u> 9f2fb7a0-59fe-4	1437-afl e-	Wallet in purse or handbag; cards stacked in holder or wallet; paper sleeve.
	Medium	2	8 <b>0</b> 1153e32	241/iso-iec-2478	9-1-2012		Hard plastic holder; cards shingled in holder or wallet; wallet in trouser pocket; soft plastic holder.
	High	5	0				Inserted in reader in vehicle; loose in pocket or bag.
Physical stress (compression)	None	0	0				Hard plastic holder.
	Low	0	1				Wallet in purse or handbag; cards stacked in holder or wallet; inserted in reader in vehicle.
	Medium	0	2				Multiple cards shingled in holder or wallet; wallet in trouser pocket.
	High	0	5				Loose in bag or pocket.
Sum (A, <i>U</i> )							

## Table 2 — Storage factors

Factor	Condition	Age	Usage	Probability <i>p</i> of condition (sum=1)	Age points (p x age)	Usage points ( <i>p</i> x usage)	Examples and guidance
Physical stress (bending, e.g.	None	0	0				PICC or VICC reader.
pressure by roller))	Low	0	1				Magnetic stripe or contact IC card reader with straight insertion path; motorized ATM reader with rollers running over the card.
	Medium	0	2				Contact IC card reader with bent insertion path <sup>a)</sup> .
	High	o TAN	3	RD PRF	VIEW		Magnetic stripe swipe reader; poor ergonomics of the reader location resulting in bending of the card during insertion/withdra wal; rough mechanical handling.
Physical stress (friction)	None https://standards.	<b>Stan</b> <u>IS</u> iteh.ai/cat 8fd153e3	O/IEC 24 <sup>°</sup> alog/standa 2241/iso-i	<b>S.itch.a</b> 1 <u>89-1:2012</u> urds/sist/9f2fb7a0 ec-24789-1-201	1 <b>)</b> -59fe-4437-af1( 2	Ç-	PICC or VICC reader; motorized card reader; low friction insertion readers.
	Low	0	1				Low friction insertion readers; magnetic stripe swipe reader, where construction and installation prevent bending of the card.
	Medium	0	2				Medium friction insertion readers, e.g. with clamping device for in-car use.
	High	0	3				Magnetic stripe swipe reader, where construction or installation results in bending of the card.

Table 3 — Reader factors

Factor Condition Age Usage Probability p Age points **Usage points** Examples of condition (p x age) (p x usage) and guidance (sum=1) Physical stress None 0 0 Insertion (impact, e.g. pressing readers. the card against a motorized contactless reader) readers; VICC readers; most PICC readers. 0 1 Magnetic stripe Low swipe reader. 2 PICC reader in 0 Medium public transport gate applications. 0 High 3 Rough mechanical handling. Reader contamination None 0 0 Most office, retail, bank and (resulting in deposits inside the reader other causing abrasion) environments. Low 1 0 Insertion or iTeh STANDARD PREVIEW swipe reader installed in dusty/sandy/oily standards.iteh.ai) environment with good maintenance and ISO/IEC 24789-1:2 )12 a low level of transactions. 9f2fb7a0-59fe 437-afle https:// andards og/standards/sis eh.ai/cata 241/iso-iec-247 9-1-2012 2 301153e32 Medium Insertion or swipe reader installed in dusty/sandy/oily environment with poor maintenance or a high level of transactions. Reader installed High 3 0 in dusty/sandy/oily environment or outdoors, with poor maintenance and a high level of transactions. Sum (A, U)

#### Table 3 (continued)

<sup>a)</sup> A bent insertion path can result both from construction of the reader as well as placement of the reader, resulting in the card being bent at the insertion slot during insertion or withdrawal.

### 4.1.2 Corrected application profile

The usage frequency and the card lifetime in the field have a strong impact on the various stresses the card will have to withstand. The age coefficient (the expected card service life in years (at least 1)) and the usage coefficient (number of uses per day + 1) shall be applied to the raw application profile (A, U) to give a corrected application profile ( $A_c$ ,  $U_c$ ) as follows:

- $A_c = A \times$  the expected card service life in years (at least 1);
- $U_c = U \times (number of uses per day + 1).$

### 4.2 Determination of the aging and usage classes

Determine the corrected application profile ( $A_c$ ,  $U_c$ ), as specified in 4.1. Then check the  $A_c$  value against Table 4 to determine the aging class of the application. Then check the  $U_c$  value against Table 5 to determine the usage class of the application.

#### Table 4 — Application aging class

A <sub>c</sub> value	Aging class
0 – 10	0
> 10 – 20	1
> 20 – 50	2
> 50 iTeh STAN	BARD PREVIEW

## (standards.iteh.ai)

### Table 5 — Application usage class

<i>U</i> <sub>c</sub> value	https://standards.iteh.ai/catalo	gUsagedctas/Sf2fb7a0-59fe-4437-afle-
0 – 10	8101556522	A A A A A A A A A A A A A A A A A A A
> 10 – 20		В
> 20 – 50		С
> 50		D

## 5 Determination of the evaluation regime

### 5.1 General

Once the application profile has been specified, it is necessary to define the evaluations to be performed.

Two kinds of evaluation regime may be used to evaluate card service life:

- stand alone methods;
- evaluation sequences.

Stand alone methods are performed on card samples and the results are directly interpreted as an indication of the card's performance.

An evaluation sequence comprises a sequence of aging and usage simulation methods followed by a set of evaluation methods to determine an indication of the card's performance after exposure.

5.2 and 5.3 define evaluation regimes comprising sets of stand alone methods and evaluation sequences, respectively.

Only one of these evaluation regimes shall be selected in each case, in accordance with the guidance provided.

### 5.2 Evaluation regime using stand alone methods

This evaluation regime shall only be used when the following three conditions are met:

- the aging class is zero or one;
- the cards do not contain an IC;
- the cards are not embossed.

The evaluation methods given in Table 6, Table 7 and Table 8 may be used for all such cards.

## Table 6 — ID card flexure to produce curvature of the width of the card in accordance with 5.10 of ISO/IEC 24789-2 – Minimum cycles to stopping point

			Aging class		
			0	1	
Usage class		A	No requirement	No requirement	
		В	No requirement	10 000	
		С	10 000	25 000	
	iTeh SI	AND	25 000 PREVIE	80 000	
NOTE	Flexure to produce curvature of the width (B) axis is known in some parts of the industry as "A Flex"				

### ISO/IEC 24789-1:2012

## Table 7 — ID card flexure to produce curvature of the height of the card in accordance with 5.10 of ISO/IEC 24789-2. Minimum cycles to stopping point

			Aging class		
			0	1	
Usage class		Α	No requirement	No requirement	
		В	No requirement	5 000	
	Usage class	С	5 000	12 500	
		D	12 500	40 000	
NOTE	Elexure to produce curvature of the height (A) axis is known in some parts of the industry as "B Elex"				

## Table 8 — Temperature and humidity aging followed by peel strength in accordance with 5.11 of ISO/IEC 24789-2 - Minimum peel strength values (N/mm)

			Aging class		
			0	1	
Usage class		Α	No requirement	No requirement	
		В	No requirement	0,35 (2,00 lb <sub>f</sub> /in)	
		С	0,35 (2,00 lb <sub>f</sub> /in)	0,70 (4,00 lb <sub>f</sub> /in)	
		D	0,70 (4,00 lb <sub>f</sub> /in)	1,00 (5,71 lb <sub>f</sub> /in)	
NOTE 1	The duration of exposure to temperature and humidity aging shall be 168 hours.				
NOTE 2	Where the peel strength test fails to separate the card layers, the result exceeds the minimum requirement.				

### 5.2.1 Cards that have magnetic stripes

The following evaluation method shall only be used for cards bearing a magnetic stripe.

## Table 9 — Magnetic stripe abrasion in accordance with 5.3 of ISO/IEC 24789-2 - Minimum abrasion cycles while $U_A > 0,70 U_{A \text{ initial}}$

		Aging class	
		0	1
	Α	No Requirement	100
	В	100	200
Usage class	С	200	300
	D	300	500

### 5.2.2 Cards with surface printing and security devices

The following evaluation methods shall only be used for cards that have personalisation, printing, security devices and similar artifacts at or near the surface of the cards.

## Table 10 — Surface abrasion in accordance with 5.2 of ISO/IEC 24789-2 - Minimum cycles to stopping point

iTeh STANDARDAging class VIEW						
	(9	standards.	iteh.ai)		1	
	Α	100/100 04000	No Requirem	ient	50	
	nttps://standards.it	eh.ai/catalog/standards	- <u>1:2012</u> /sist/9f2fb7a0-5	9fe-4437-afle-	300	
Usage class	<b>C</b> 8	fd153e32241/iso-iec-2	24300-1-2012		600	
	D		600		1 000	

## Table 11 — Delamination – Cross cut tape test in accordance with 5.12 of ISO/IEC 24789-2 - Maximum grade 0 – 5 (0 = best)

		Aging class		
		0	1	
Usage class	Α	4	4	
	В	4	3	
	С	3	1	
	D	1	0	

### 5.3 Evaluation regime using evaluation sequences

The following evaluation regime may be used in all cases.

It shall be used in cases where the use of stand alone methods is not permissible i.e. where any of the following conditions are met:

— the aging class is 2 or 3;